

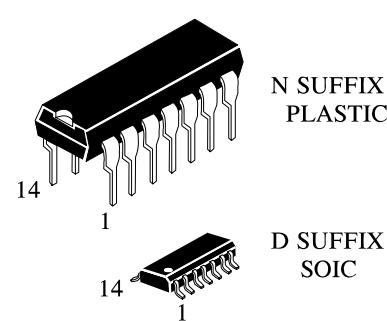
IN74HC05A

Hex Inverter with Open-Drain Outputs

The IN74HC05A is identical in pinout to the LS/ALS05. The device inputs are compatible with standard CMOS outputs; with pullup resistors, they are compatible with LS/ALSTTL outputs.

This device contains six independent gates, each of which performs the logic INVERT function. The open-drain outputs require external pull-up resistors for proper logical operation. They may be connected to other open-drain outputs to implement active-high wired-AND functions.

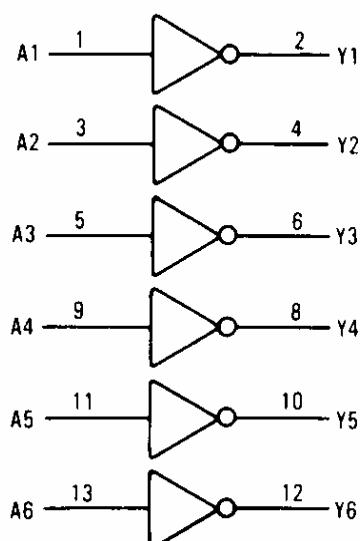
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 2.0 to 6.0 V
- Low Input Current: 1.0 μ A
- High Noise Immunity Characteristic of CMOS Devices

**ORDERING INFORMATION**

IN74HC05AN Plastic

IN74HC05AD SOIC

IZ74HC05AZ Chip

 $T_A = -55^\circ$ to 125° C for all packages**LOGIC DIAGRAM****PIN ASSIGNMENT**

A1	1 ●	14	V _{CC}
Y1	2	13	A6
A2	3	12	Y6
Y2	4	11	A5
A3	5	10	Y5
Y3	6	9	A4
GND	7	8	Y4

FUNCTION TABLE

Inputs	Output
A	Y
L	Z
H	L

Z = High Impedance

PIN 14 = V_{CC}
PIN 7 = GND



INTEGRAL

MAXIMUM RATINGS*

Symbol	Parameter	Value	Unit
V _{CC}	DC Supply Voltage (Referenced to GND)	-0.5 to +7.0	V
V _{IN}	DC Input Voltage (Referenced to GND)	-1.5 to V _{CC} +1.5	V
V _{OUT}	DC Output Voltage (Referenced to GND)	-0.5 to V _{CC} +0.5	V
I _{IN}	DC Input Current, per Pin	±20	mA
I _{OUT}	DC Output Current, per Pin	±25	mA
I _{CC}	DC Supply Current, V _{CC} and GND Pins	±50	mA
P _D	Power Dissipation in Still Air, Plastic DIP** SOIC Package**	750 500	mW
T _{stg}	Storage Temperature	-65 to +150	°C
T _L	Lead Temperature, 1 mm from Case for 10 Seconds (Plastic DIP or SOIC Package)	260	°C

*Maximum Ratings are those values beyond which damage to the device may occur.

Functional operation should be restricted to the Recommended Operating Conditions.

**Derating - Plastic DIP: - 10 mW/°C from 65° to 125°C

SOIC Package: - 7 mW/°C from 65° to 125°C

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit	
V _{CC}	DC Supply Voltage (Referenced to GND)	2.0	6.0	V	
V _{IN} , V _{OUT}	DC Input Voltage, Output Voltage (Referenced to GND)	0	V _{CC}	V	
T _A	Operating Temperature, All Package Types	-55	+125	°C	
t _r , t _f	Input Rise and Fall Time (Figure 1)	V _{CC} =2.0 V V _{CC} =4.5 V V _{CC} =6.0 V	0 0 0	1000 500 400	ns

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{IN} and V_{OUT} should be constrained to the range GND≤(V_{IN} or V_{OUT})≤V_{CC}.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or V_{CC}). Unused outputs must be left open.

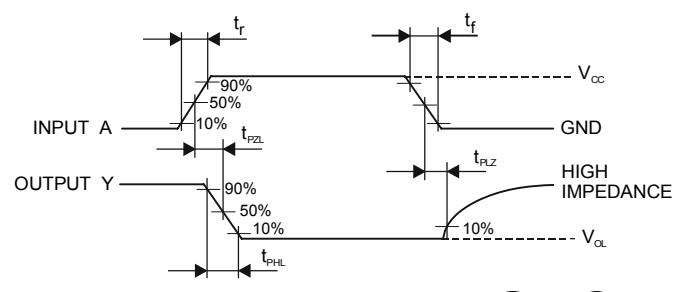
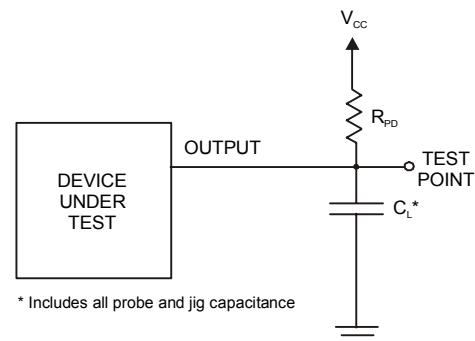
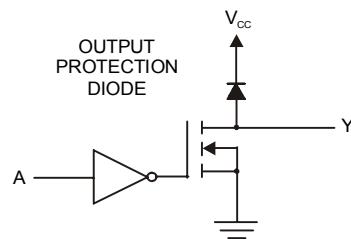
DC ELECTRICAL CHARACTERISTICS(Voltages Referenced to GND)

Symbol	Parameter	Test Conditions	Vcc V	Guaranteed Limit			Unit
				25 °C to -55°C	≤85 °C	≤125 °C	
V _{IL}	Low -Level Input Voltage	V _{OUT} = V _{CC} or 0 V I _{OUT} ≤ ±0.5 μA (θ= -55 to 25°C) I _{OUT} ≤ ±5.0 μA (θ= 85°C) I _{OUT} ≤ ±10 μA (θ= 125°C)	2.0 4.5 6.0	0.5 1.35 1.8	0.5 1.35 1.8	0.5 1.35 1.8	V
V _{IH}	High-Level Input Voltage	V _{OUT} ≤ 0.1 V I _{OUT} ≤ 20 μA	2.0 4.5 6.0	1.5 3.15 4.2	1.5 3.15 4.2	1.5 3.15 4.2	V
V _{OL}	Low - Level Output Voltage	V _{IN} =V _{IH} I _{OUT} ≤ 20 μA	2.0 4.5 6.0	0.1 0.1 0.1	0.1 0.1 0.1	0.1 0.1 0.1	V
		V _{IN} =V _{IH} I _{OUT} ≤ 4.0 mA	4.5	0.26	0.33	0.4	
		V _{IN} =V _{IH} I _{OUT} ≤ 5.2 mA	6.0	0.26	0.33	0.40	
I _{IL}	Input Leakage Current	V _{IL} = GND	6.0	-0.1	-1.0	-1.0	μA
I _{IH}	Input Leakage Current	V _{IH} =V _{CC}	6.0	-0.1	-1.0	-1.0	μA
I _{CC}	Quiescent Supply Current (per Package)	V _{IL} =GND V _{IH} =V _{CC} I _{OUT} =0 μA	6.0	1.0	10	40	μA
I _{OZL}	Three-State Leakage Current	V _{IN} = V _{IL} or V _{IH} V _{OUT} = GND	6.0	-0.5	-5.0	-10	μA
I _{OZH}	Three-State Leakage Current	V _{IN} = V _{IL} or V _{IH} V _{OUT} = V _{CC}	6.0	-0.5	-5.0	-10	μA

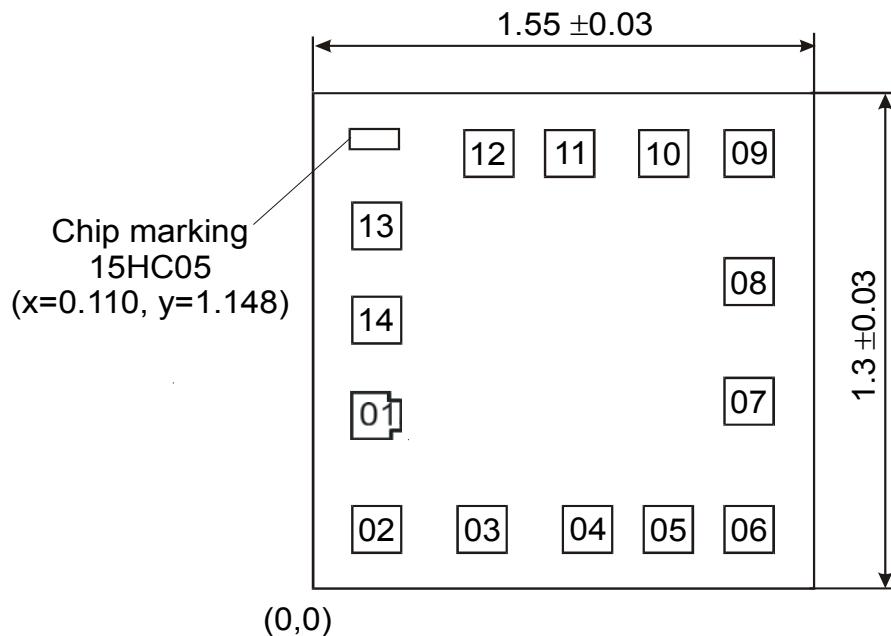
AC ELECTRICAL CHARACTERISTICS($C_L = 50\text{ pF}$, Input $t_r = t_f = 6.0\text{ ns}$)

Symbol	Parameter	Test Conditions	V _{CC} V	Guaranteed Limit			Unit
				25 °C to -55°C	≤85 °C	≤125 °C	
t_{PLZ}, t_{PZL}	Propagation Delay, Input A to Output Y (Figures 1 and 2)	$V_{IL} = \text{GND}$ $V_{IH} = V_{CC}$ $t_{LH} = t_{HL} = 6\text{ ns}$ $C_L = 50\text{ pF}$	2.0 4.5 6.0	120 24 20	150 30 26	180 36 31	ns
t_{THL}	Output Transition Time, Any Output (Figures 1 and 2)	$V_{IL} = \text{GND}$ $V_{IH} = V_{CC}$ $t_{LH} = t_{HL} = 6\text{ ns}$ $C_L = 50\text{ pF}$	2.0 4.5 6.0	75 15 13	95 19 16	110 22 19	ns
C_{IN}	Input Capacitance			10	10	10	pF
C_{OUT}	Three-State Output Capacitance (Output in High- Impedance State)			10	10	10	pF

C_{PD}	Power Dissipation Capacitance (Per Gate)	Typical @25°C, $V_{CC} = 5.0\text{ V}$	pF
	Used to determine the no-load dynamic power consumption: $P_D = C_{PD}V_{CC}^2f + I_{CC}V_{CC}$	8.0	

**Figure 1. Switching Waveforms****Figure 2. Test Circuit****Figure 3. Expanded Logic Diagram (1/6 of the Device)**

CHIP PAD DIAGRAM IZ74HC05A



Pad size 0.106 x 0.106 mm (Pad size is given as per passivation layer)
Thickness of chip 0,46±0,02 mm

PAD LOCATION

Pad No	Symbol	X	Y
01	A1	0.126	0.492
02	Y1	0.136	0.122
03	A2	0.432	0.112
04	Y2	0.793	0.112
05	A3	0.948	0.112
06	Y3	1.312	0.112
07	GND	1.312	0.471
08	Y4	1.312	0.643
09	A4	1.312	1.062
10	Y5	1.107	1.062
11	A5	0.747	1.062
12	Y6	0.492	1.062
13	A6	0.126	0.941
14	Vcc	0.126	0.747